

Description

This is -40V -50A P-Channel Enhancement mode power mosfet in a DFN3.3*3.3-8L plastic package.

CT50P04ZI uses advanced power trench technology that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Applications

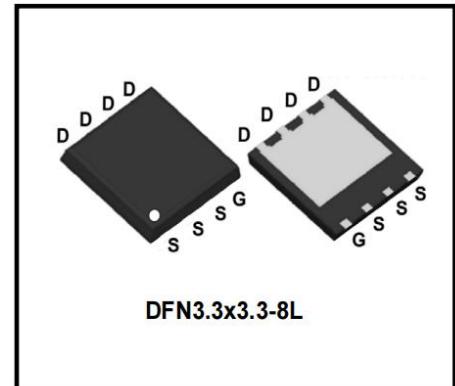
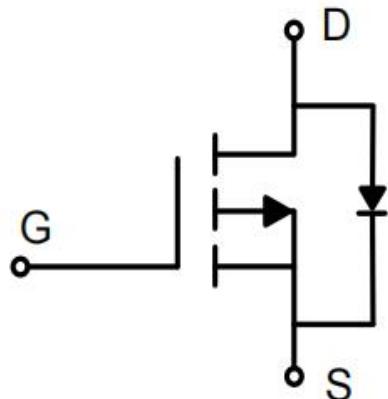
- Power Management Switches
- DC/DC converters

Features

- V_{DS} = -40V, I_D = -50A
R_{DS(on)} < 8.5mΩ @ V_GS = -10V
R_{DS(on)} < 11mΩ @ V_GS = -4.5V
- Green Device Available
- Low Gate Charge
- 100% EAS Guaranteed

| V _{DS} | R _{DS(on)(typ)} | I _D |
|-----------------|--------------------------|----------------|
| -40V | 6.8mΩ | -50 A |

Equivalent Circuit & Pinning



Absolute Maximum Ratings (TA = 25°C, unless otherwise noted)

| Parameter | Symbol | Value | Unit |
|--|-----------------------------------|------------|------|
| Drain-Source Voltage | V _{DS} | -40 | V |
| Gate-Source Voltage | V _{GS} | ±20 | V |
| Continuous Drain Current | I _D | -50 | A |
| T _c =100°C | | -32 | |
| Pulsed Drain Current ¹ | I _{DM} | -200 | A |
| Single Pulse Avalanche Energy ² | E _{AS} | 125 | mJ |
| Total Power Dissipation | P _D | 35.7 | W |
| Operating Junction and Storage Temperature Range | T _J , T _{STG} | -55 to 150 | °C |

Thermal Characteristics

| Parameter | Symbol | Value | Unit |
|--|------------------|-------|------|
| Thermal Resistance from Junction-to-Ambient ³ | R _{θJA} | 56 | °C/W |
| Thermal Resistance from Junction-to-Case | R _{θJC} | 3.5 | °C/W |

Electrical Characteristics (T_J = 25° C, unless otherwise noted)

| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Unit |
|---|----------------------|--|------|------|------|------|
| Static Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | V _{(BR)DSS} | V _{GS} = 0V, I _D = -250μA | -40 | - | - | V |
| Gate-body Leakage current | I _{GSS} | V _{DS} = 0V, V _{GS} = ±20V | - | - | ±100 | nA |
| Zero Gate Voltage Drain Current T _J =25°C | I _{DSS} | V _{DS} = -40V, V _{GS} = 0V | - | - | -1 | μA |
| T _J =100°C | | | - | - | -100 | |
| Gate-Threshold Voltage | V _{GS(th)} | V _{DS} = V _{GS} , I _D = -250μA | -1.0 | -1.6 | -2.5 | V |
| Drain-Source on-Resistance ⁴ | R _{DS(on)} | V _{GS} = -10V, I _D = -20A | - | 6.8 | 8.5 | mΩ |
| | | V _{GS} = -4.5V, I _D = -15A | - | 8.5 | 11 | |
| Forward Transconductance ⁴ | g _{fS} | V _{DS} = -10V, I _D = -20A | - | 104 | - | S |
| Dynamic Characteristics⁵ | | | | | | |
| Input Capacitance | C _{iss} | V _{DS} = -20V, V _{GS} = 0V, f = 1MHz | - | 5295 | - | pF |
| Output Capacitance | C _{oss} | | - | 430 | - | |
| Reverse Transfer Capacitance | C _{rss} | | - | 385 | - | |
| Gate Resistance | R _g | f = 1MHz | - | 4.1 | - | Ω |
| Switching Characteristics⁵ | | | | | | |
| Total Gate Charge | Q _g | V _{GS} = -10V, V _{DS} = -20V, I _D = -20A | - | 110 | - | nC |
| Gate-Source Charge | Q _{gs} | | - | 12.5 | - | |
| Gate-Drain Charge | Q _{gd} | | - | 23 | - | |
| Turn-on Delay Time | t _{d(on)} | V _{GS} = -10V, V _{DD} = -20V, R _G = 3Ω, I _D = -20A | - | 16.8 | - | ns |
| Rise Time | t _r | | - | 10 | - | |
| Turn-off Delay Time | t _{d(off)} | | - | 65 | - | |
| Fall Time | t _f | | - | 17 | - | |
| Body Diode Reverse Recovery Time | t _{rr} | I _F = -20A, dI/dt = -100A/μs | - | 42 | - | ns |
| Body Diode Reverse Recovery Charge | Q _{rr} | | - | 29 | - | nC |
| Drain-Source Body Diode Characteristics | | | | | | |
| Diode Forward Voltage ⁴ | V _{SD} | I _S = -20A, V _{GS} = 0V | - | - | -1.2 | V |
| Continuous Source Current | I _S | T _C =25°C | - | - | -50 | A |

Notes:

- Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150°C.
- The EAS data shows Max. rating . The test condition is V_{DD}= -25V, V_{GS}= -10V, L= 0.4mH, I_{AS}= -50A.
- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
- The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
- This value is guaranteed by design hence it is not included in the production test.

Typical Characteristic

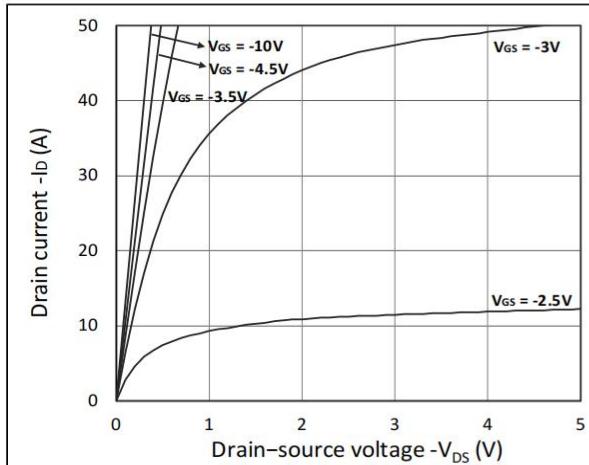


Figure 1. Output Characteristics

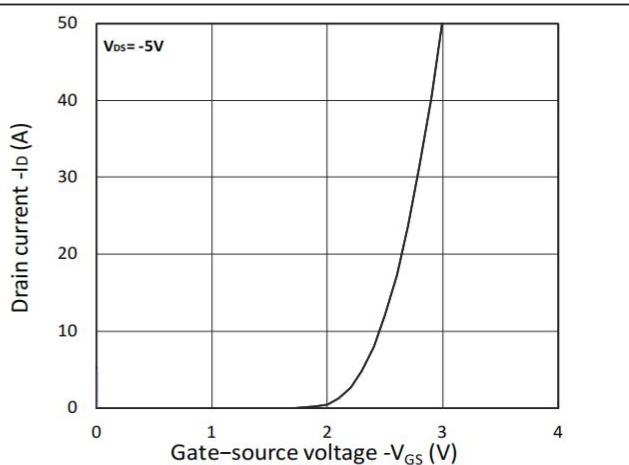


Figure 2. Transfer Characteristics

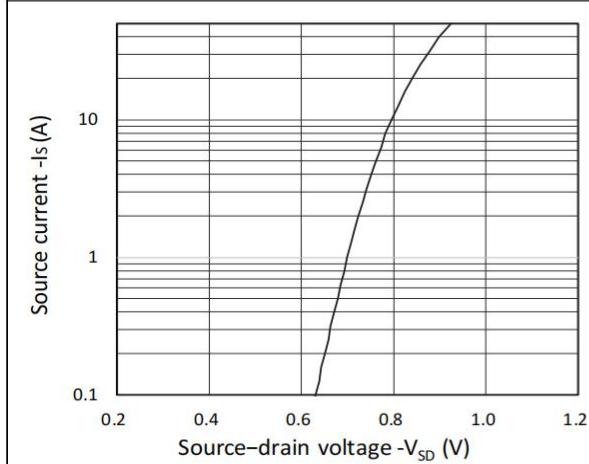


Figure 3. Forward Characteristics of Reverse

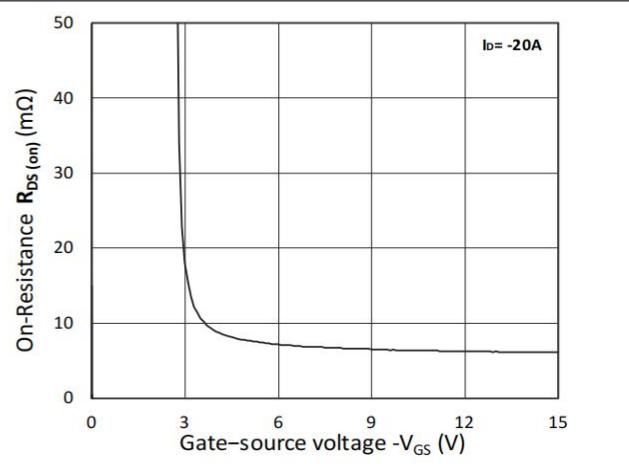


Figure 4. $R_{DS(on)}$ vs. V_{GS}

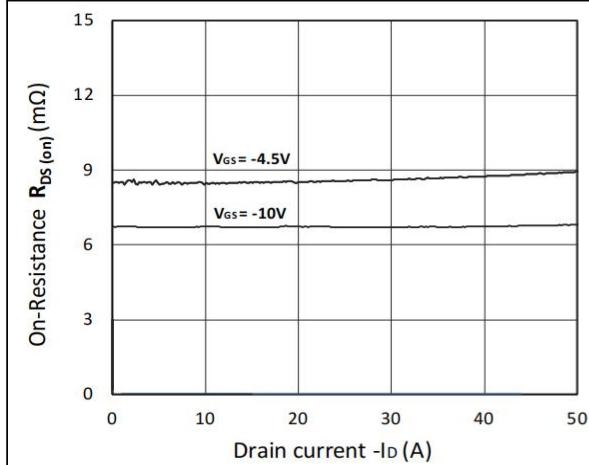


Figure 5. $R_{DS(on)}$ vs. I_D

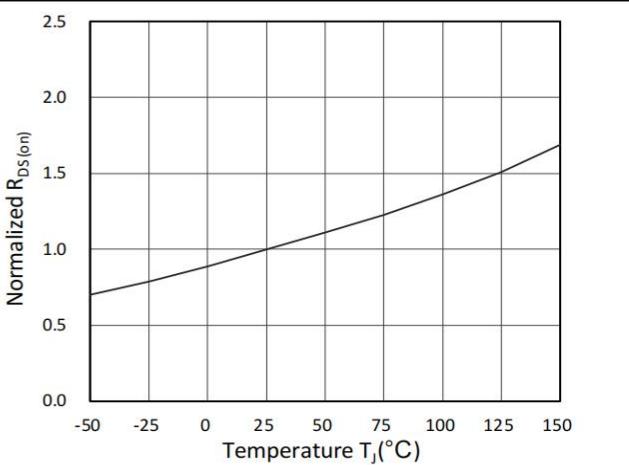
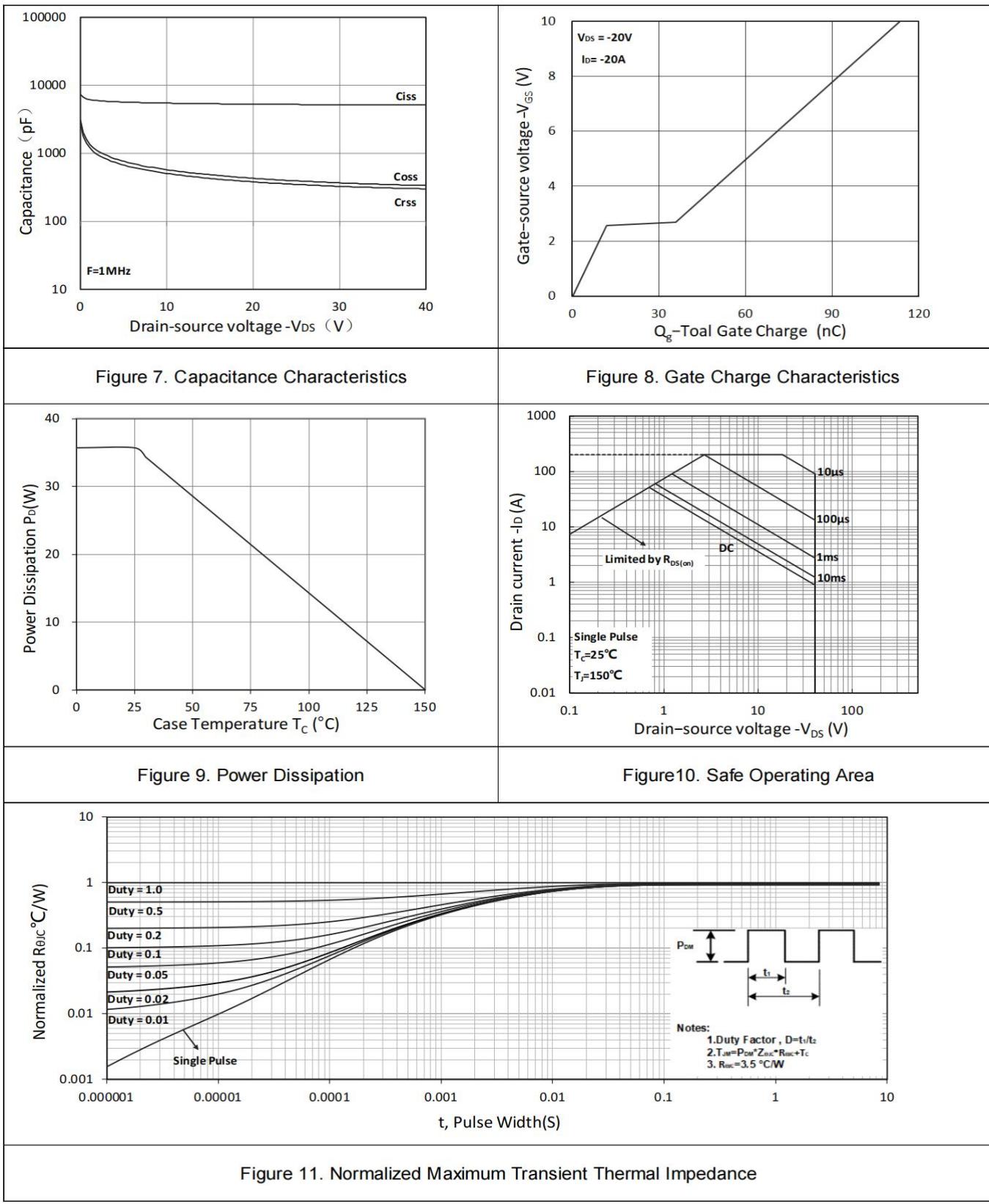
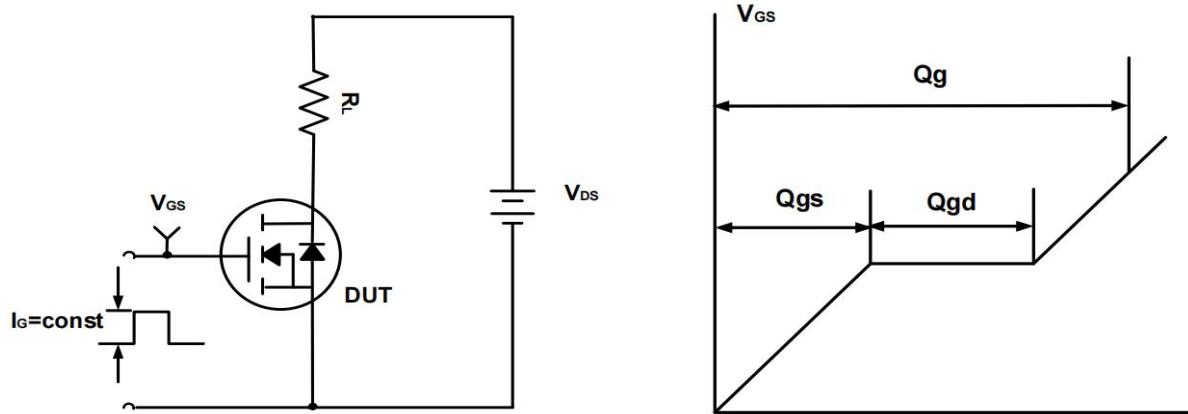
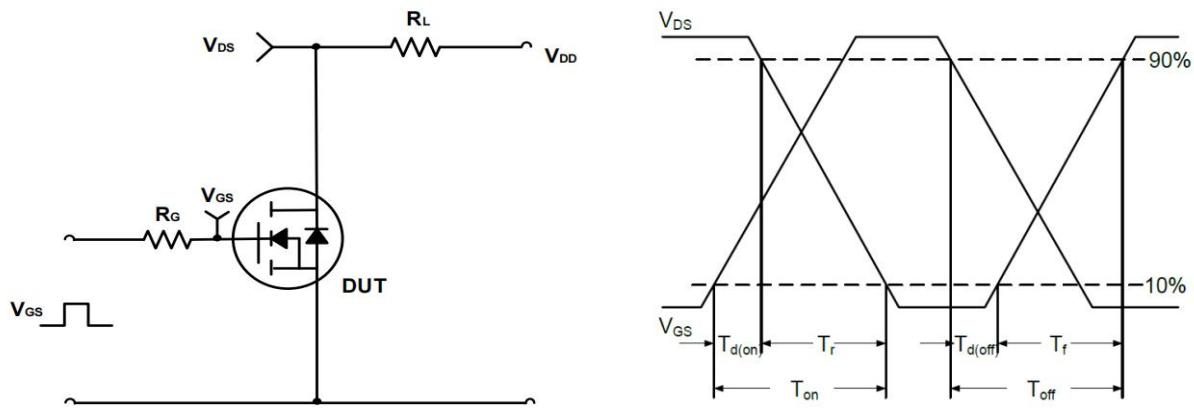
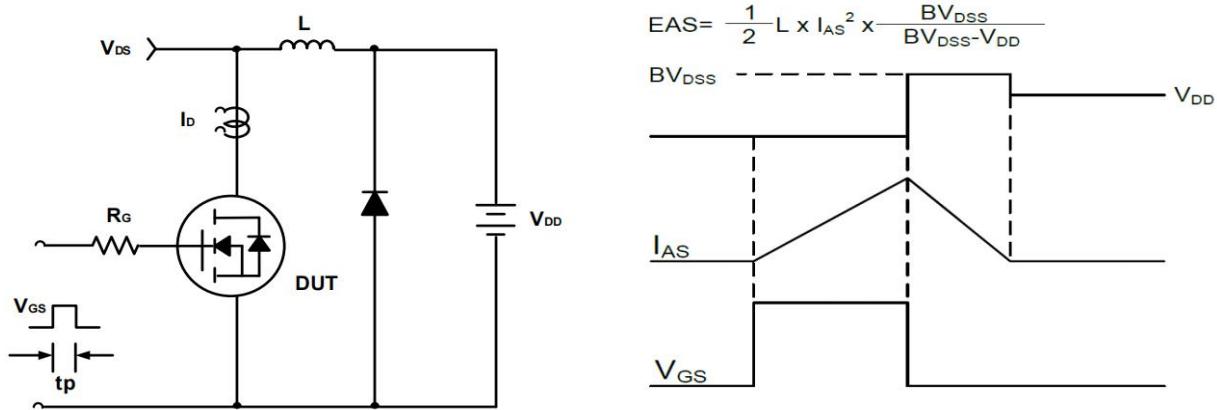


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

Typical Characteristic



Test Circuit

Figure A. Gate Charge Test Circuit & Waveforms

Figure B. Switching Test Circuit & Waveforms

Figure C. Unclamped Inductive Switching Circuit & Waveforms

Marking Information

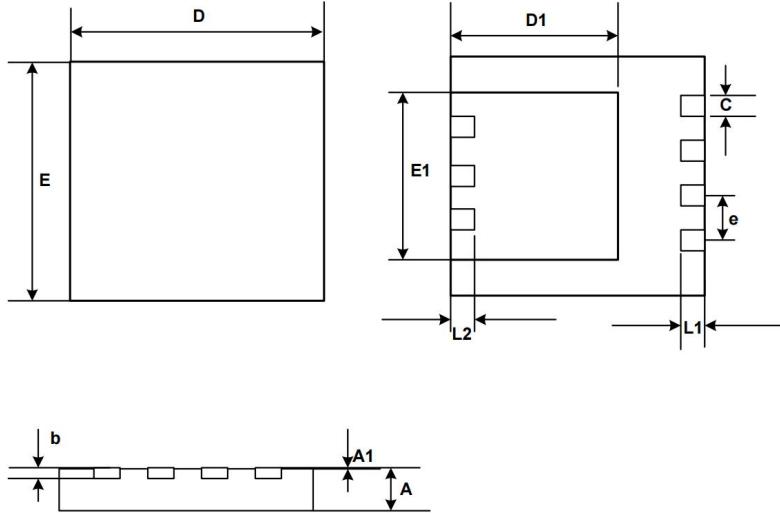


50P04= Device code

XX XXXXX= Date code

Ordering Information

| Part | Package | Marking | Packing method |
|-----------|---------------|---------|----------------|
| CT50P04ZI | DFN3.3x3.3-8L | 50P04 | Tape and Reel |

Mechanical Dimensions for DFN3.3*3.3-8L

COMMON DIMENSIONS

| SYMBOL | MM | |
|--------|-----------|-------|
| | MIN | MAX |
| A | 0.700 | 0.800 |
| A1 | 0.000 | 0.050 |
| b | 0.216 REF | |
| c | 0.290 | 0.390 |
| e | 0.65BSC | |
| D | 3.200 | 3.400 |
| D1 | 2.020 | 2.220 |
| E | 3.200 | 3.400 |
| E1 | 2.190 | 2.390 |
| F | 0.405 | 0.605 |
| L1 | 0.350 | 0.550 |
| L2 | 0.300 | 0.500 |